



CAN CROSS SECTIONS BE ACCURATELY KNOWN A PRIORI?

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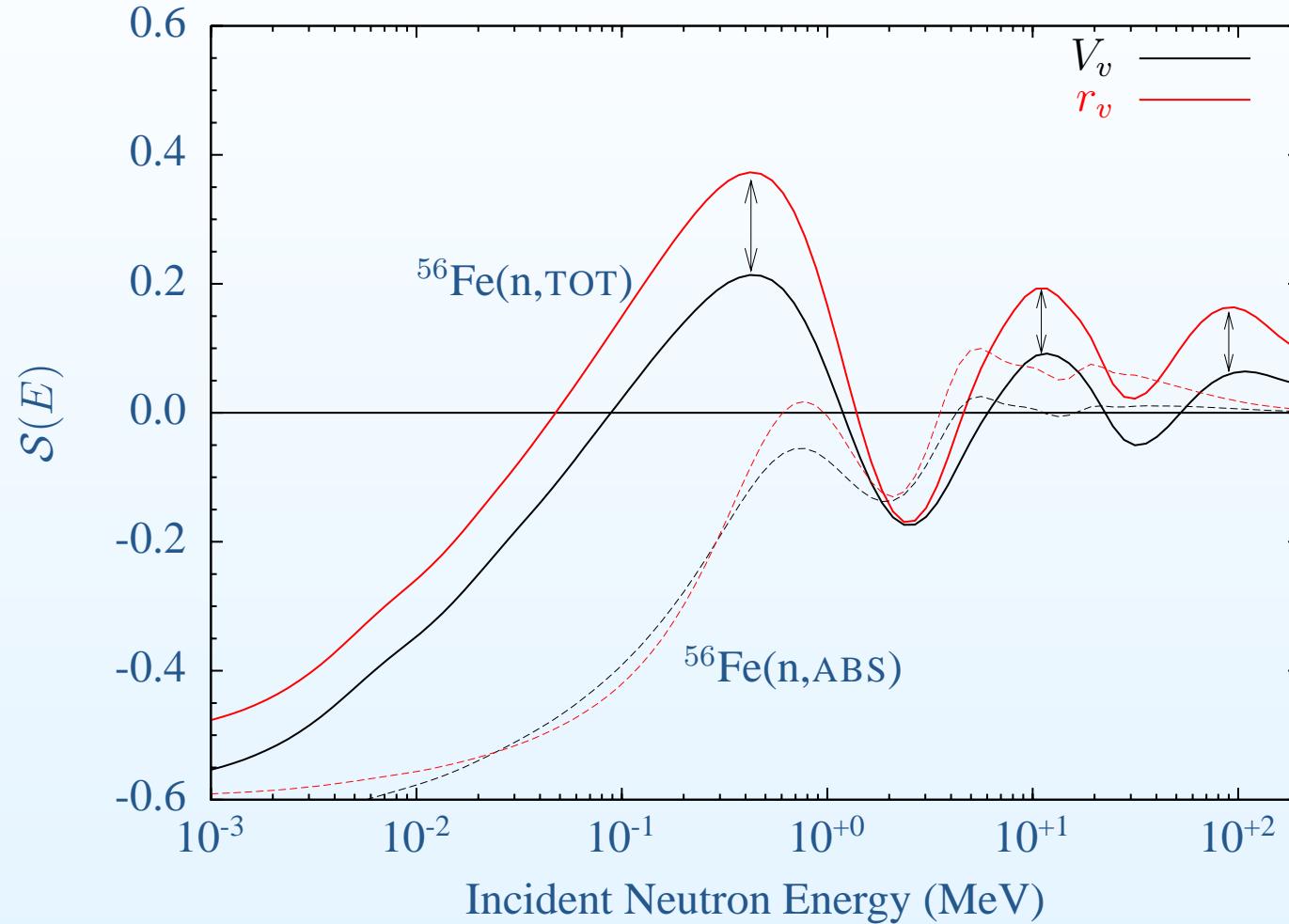
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- CORRELATION
- RESULTS
- FORMALISM
- ARGAND
- SENSITIVITY
- CONCLUSION

INTRODUCTION

- ✓ In the “low-fidelity covariance project” families of distinct maxima and minima were observed in the neutron total cross-section uncertainties between 5 keV and 20 MeV.
- ✓ These oscillations were seen to result mostly from the perturbation of V_v , the real volume depth.
- ✓ To investigate their origin, we calculated total cross sections perturbing V_v by its expected uncertainty $\pm \Delta V_v$ and inspecting the effect of this perturbation on the partial wave cross sections.
- ✓ From the total cross-section uncertainty analysis, we tried to get implications on the total reaction cross sections (absorption).

PARAMETER CORRELATION: V_v, r_v

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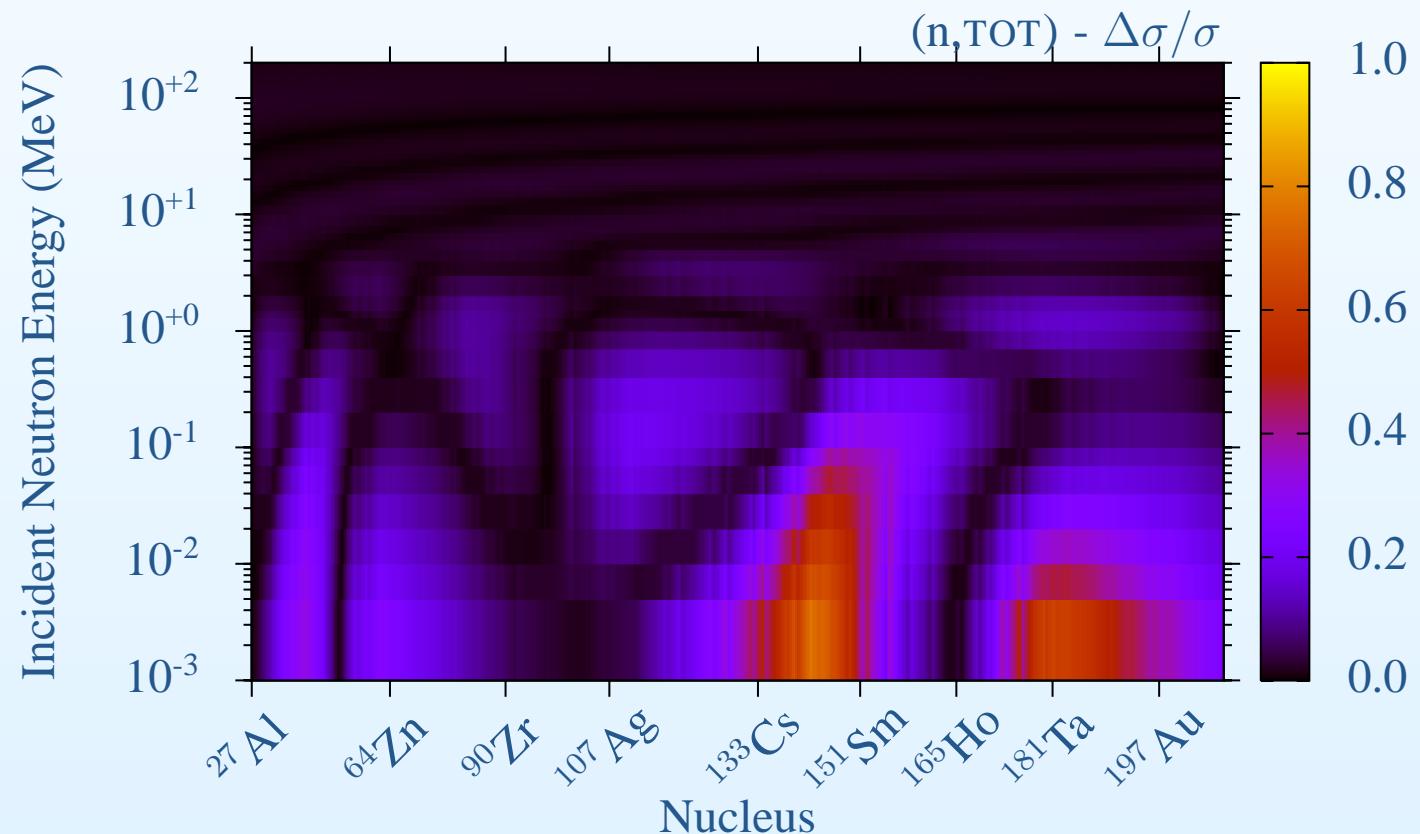


- Almost complete correlation between V_v and r_v
- Total cross section dependence like $V_v r_v^2$

RESULTS: MATERIALS FROM ^{27}Al TO ^{210}Bi

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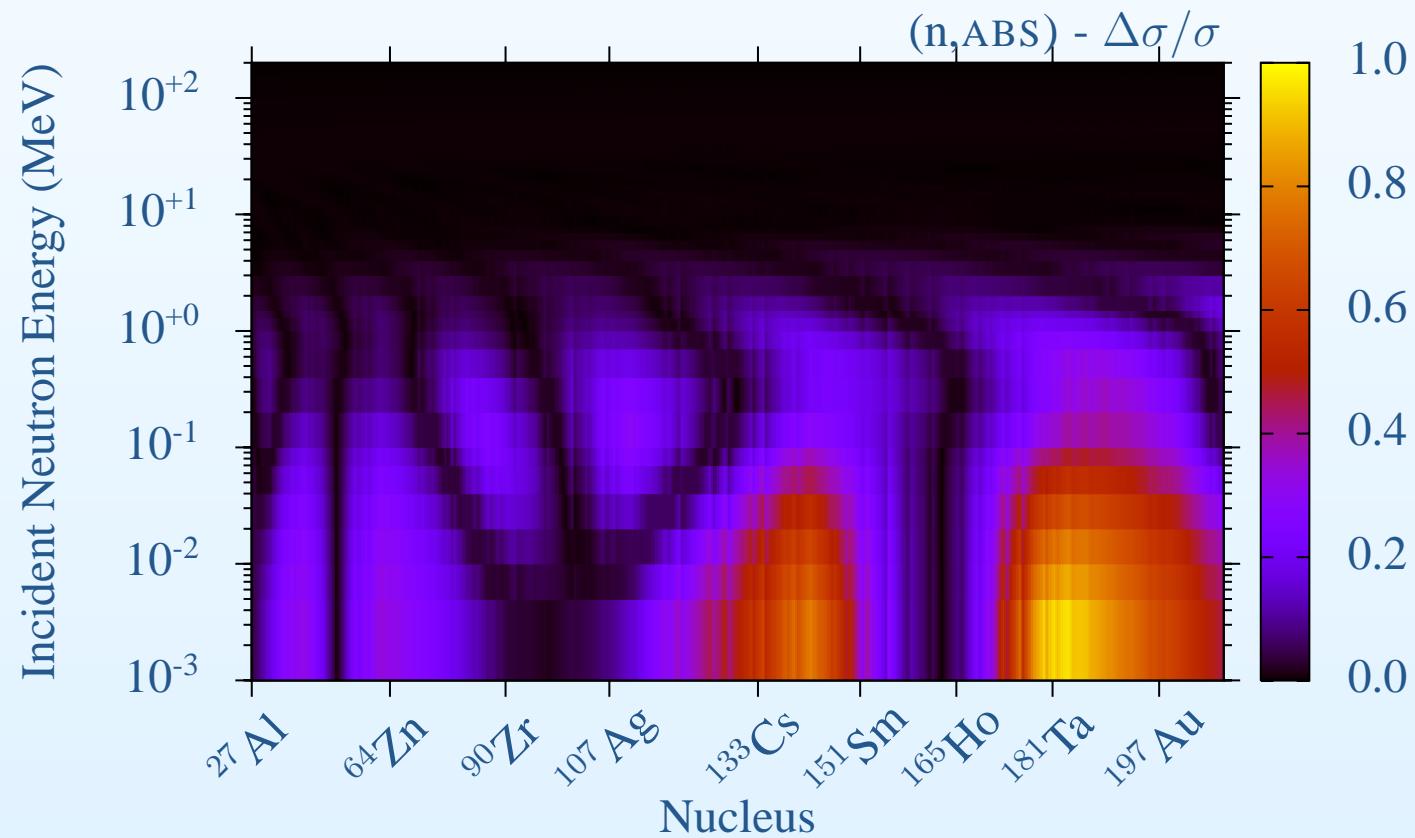
$$(\Delta\sigma_{\text{TOT}})^2 = \frac{\partial\sigma_{\text{TOT}}}{\partial V_v} (\Delta V_v)^2 \frac{\partial\sigma_{\text{TOT}}}{\partial V_v}, \quad \Delta V_v = \pm 3\%$$



RESULTS: MATERIALS FROM ^{27}Al TO ^{210}Bi

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$$(\Delta\sigma_{\text{ABS}})^2 = \frac{\partial\sigma_{\text{ABS}}}{\partial V_v} (\Delta V_v)^2 \frac{\partial\sigma_{\text{ABS}}}{\partial V_v}, \quad \Delta V_v = \pm 3\%$$



S-MATRIX FORMALISM

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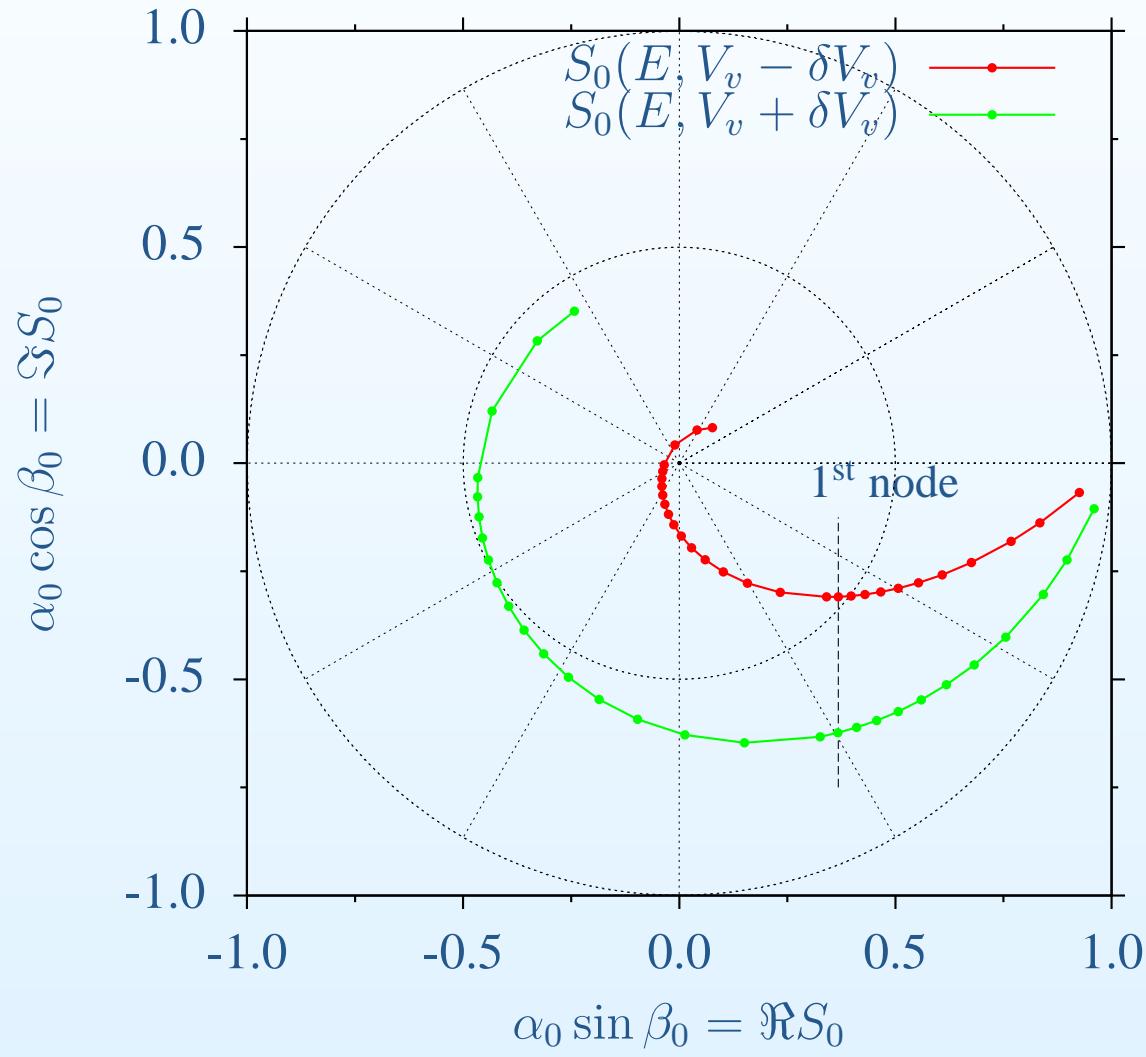
$$S_\ell^\pm(\lambda) = e^{2i\eta_\ell^\pm(\lambda)} = \alpha_\ell^\pm(\lambda)e^{i\beta_\ell^\pm(\lambda)} \quad \alpha_\ell, \beta_\ell \in \mathbb{R}$$

$$\begin{aligned}\sigma_{\text{TOT}} &= \frac{\lambda^2}{2\pi} \sum_{\ell=0}^{+\infty} (\ell+1)(1 - \Re S_\ell^+) + \ell(1 - \Re S_\ell^-), \\ \sigma_{\text{ABS}} &= \frac{\lambda^2}{\pi} \sum_{\ell=0}^{+\infty} (\ell+1)(1 - |S_\ell^+|^2) + \ell(1 - |S_\ell^-|^2), \\ \sigma_{\text{EL}} &= \frac{\lambda^2}{\pi} \sum_{\ell=0}^{+\infty} (\ell+1)|1 - S_\ell^+|^2 + \ell|1 - S_\ell^-|^2.\end{aligned}$$

ARGAND DIAGRAM FOR $\ell = 0$

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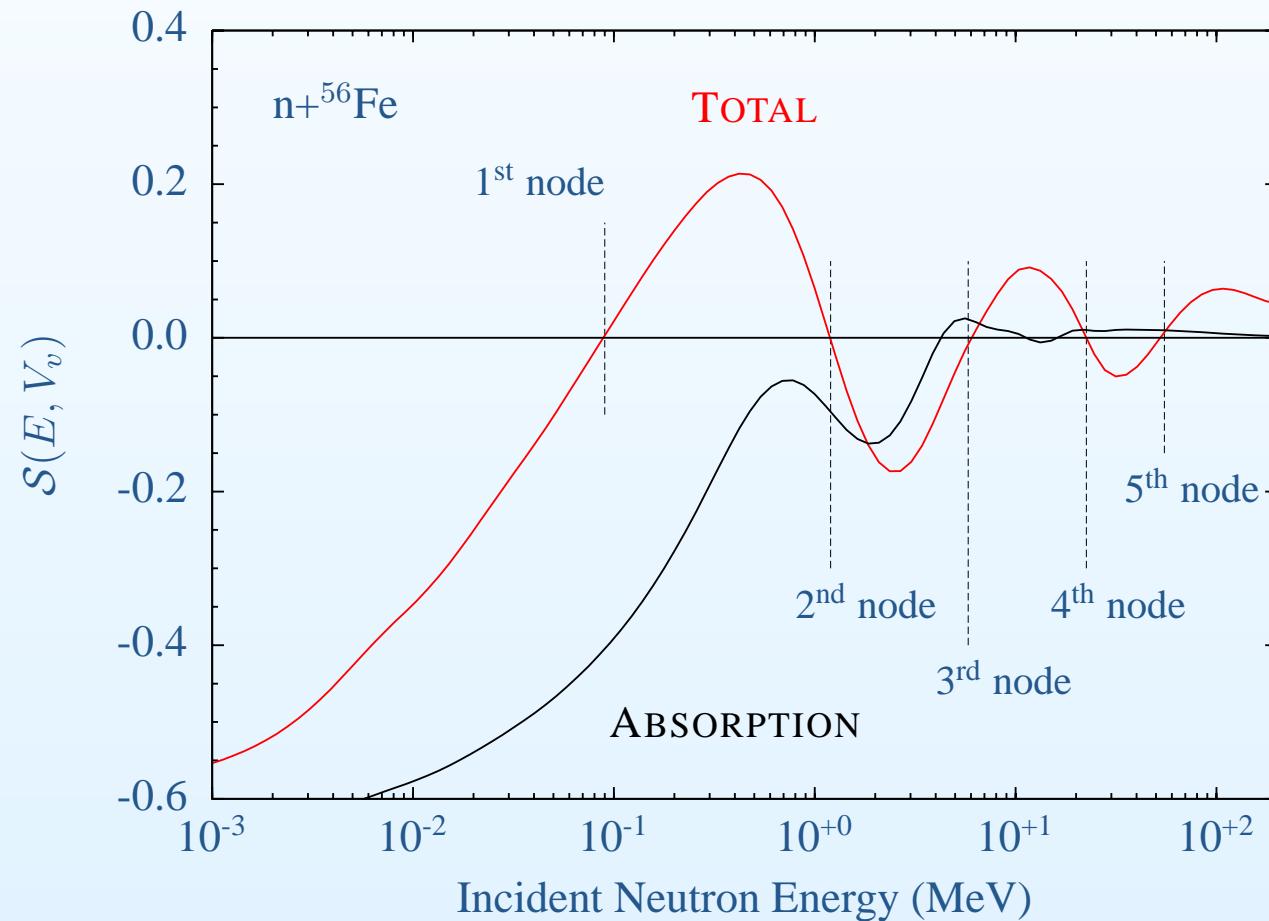
$$S_0 \equiv e^{2i\eta_0} = \alpha_0 e^{i\beta_0} = \alpha_0 (\cos \beta_0 + i \sin \beta_0)$$



SENSITIVITY PLOTS

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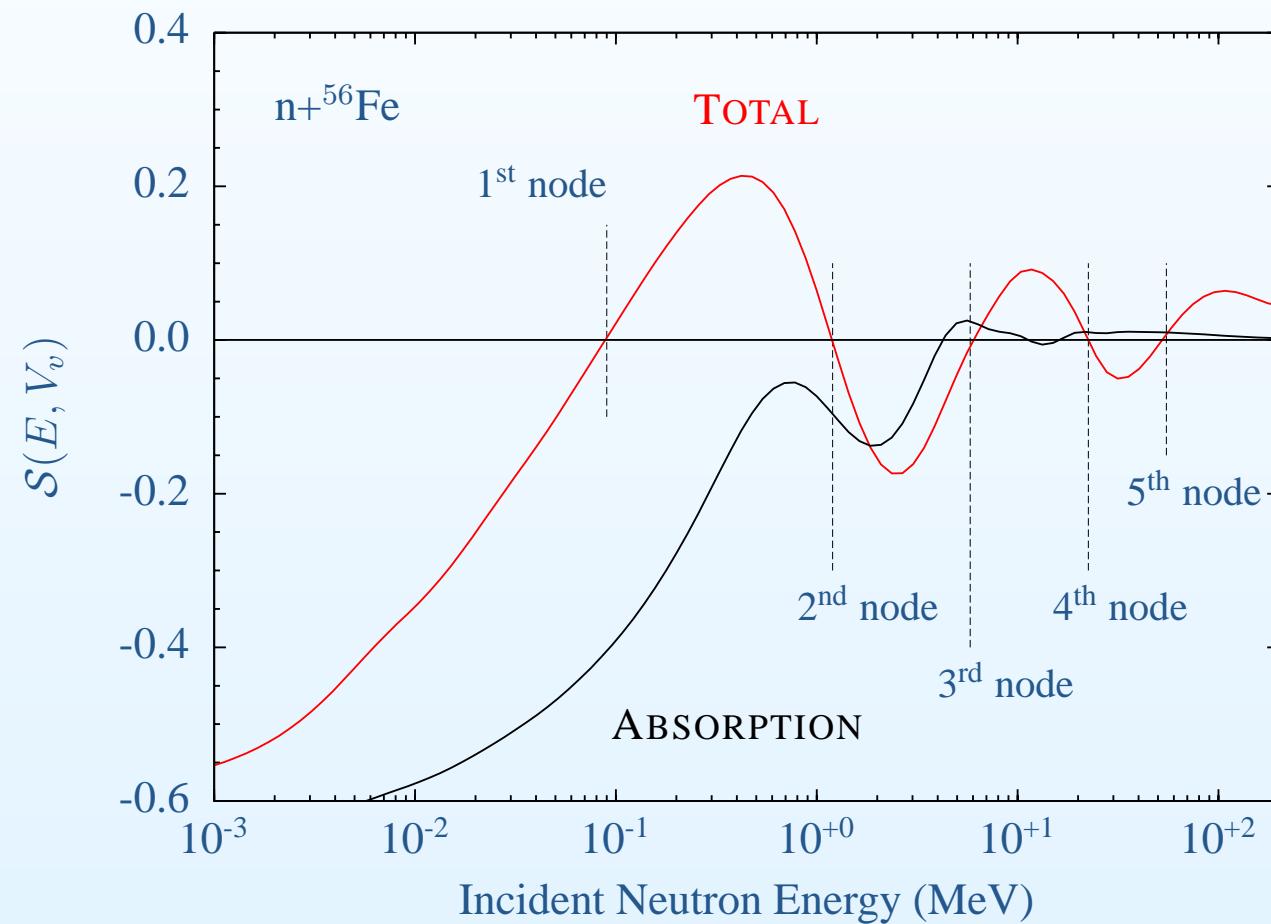
$$\mathcal{S}(E, V_v) = 2 \cdot \frac{\delta V_v}{\sigma} \cdot \frac{\partial \sigma}{\partial V_v} = 2 \cdot \frac{\delta V_v}{\sigma} \cdot \sum_{\ell=0}^{+\infty} \frac{\partial \sigma_\ell}{\partial V_v}$$



SENSITIVITY PLOTS

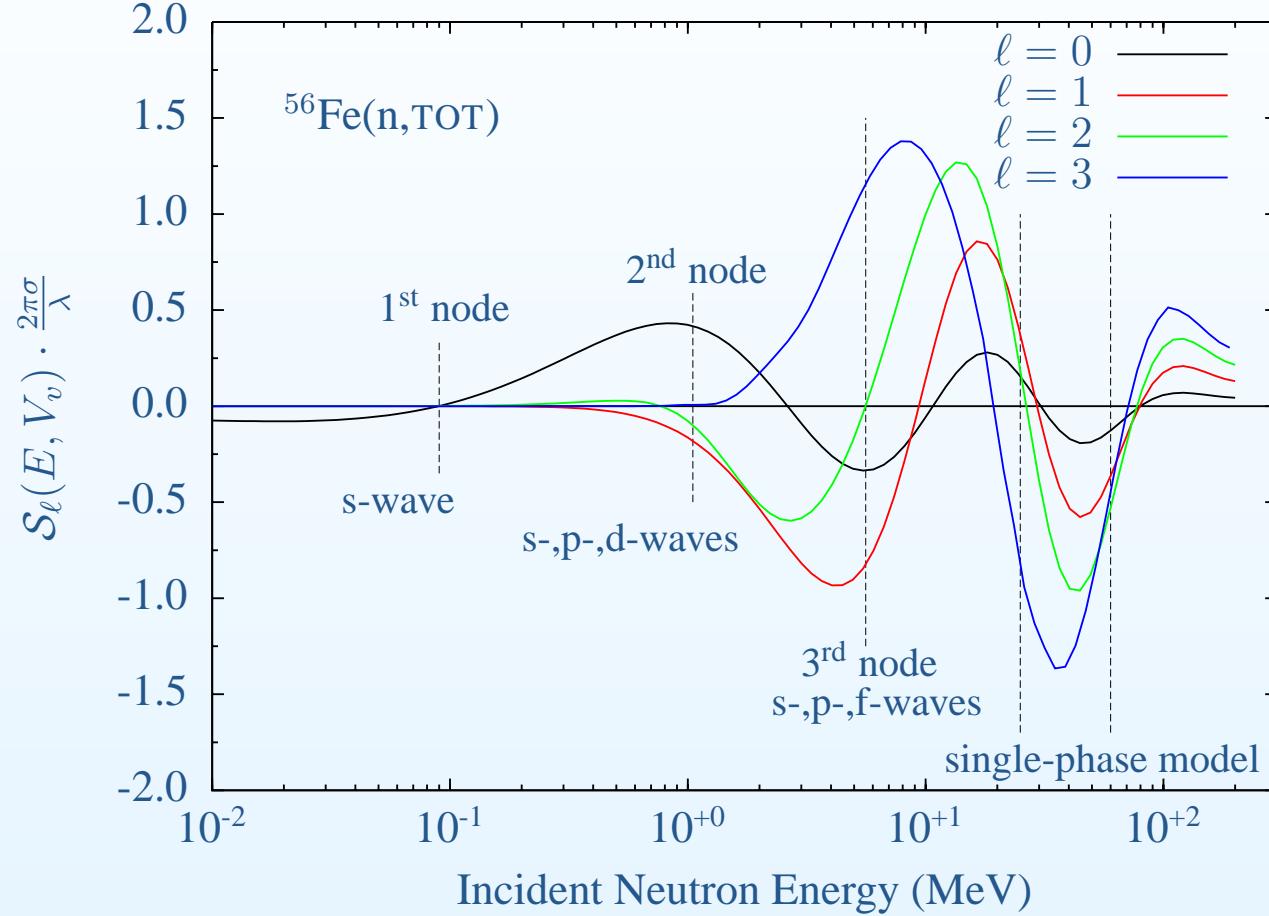
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- Maxima and minima in TOTAL do not correspond in ABSORPTION



SENSITIVITY PLOTS

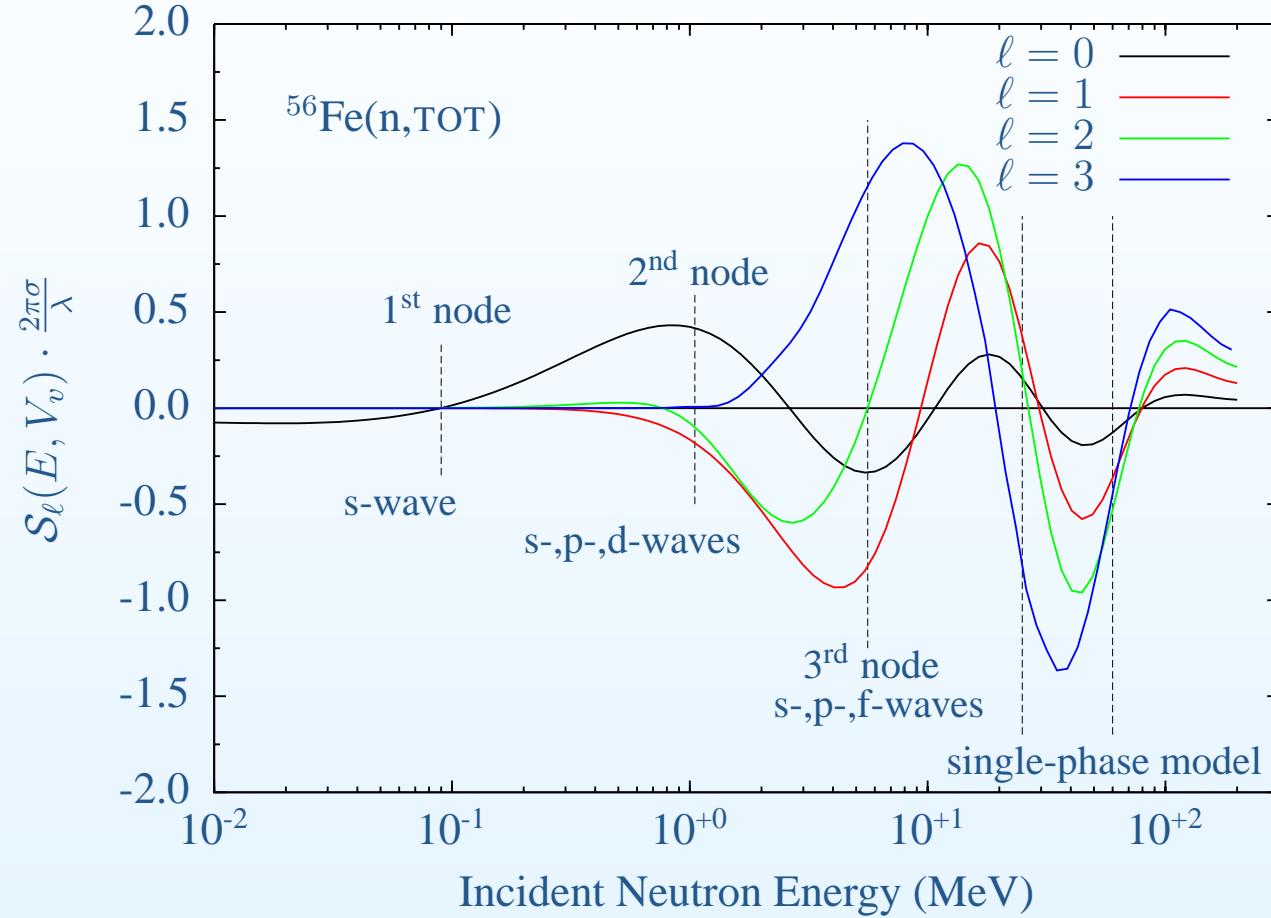
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- $\lesssim 7$ MeV interplay among s-, p-, d-, ... partial waves

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- Single-phase model (i.e. Ramsauer effect) assumes effective S-matrix - $S_{\text{eff}} \equiv e^{2i\eta} = \alpha e^{i\beta}$ - independent from ℓ .

CONCLUSIONS AND OUTLOOK

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- ✓ We generate a very comprehensive set of cross section uncertainties (about 650 materials) in order to explain the oscillating patterns found in the previous “low-fidelity covariance project”.
- ✓ The sensitivity analysis on two optical parameters, V_v and r_v , confirmed their almost complete correlation in the (n,TOT) channel ($E \gtrsim$ a few MeV), but not necessary in the reaction cross section.
- ✓ We explained the origin of these minima in terms of the interplay of a few partial waves (low-energy) and the single-channel model ($E \gtrsim$ a few MeV).
- In the future, we intend to ultimate the partial-waves analysis for the complete set of materials and, eventually, to find a systematic on the A-mass number.